

## Yes, it is that simple.

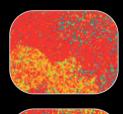
Instant EDS analysis at the press of a button.

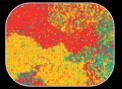
With the NORAN System SIX X-ray Microanalysis System from Thermo Electron Corporation, all it takes is a single button press to go from Sample to Answers in an instant. New and exclusive Direct to Phase software combines the steps of setting up the acquisition, waiting for the data to be collected and producing the results into a single, integrated procedure.

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Learn more about how the NORAN System SIX saves you time at www.thermo.com/microanalysis.

Look closer for answers





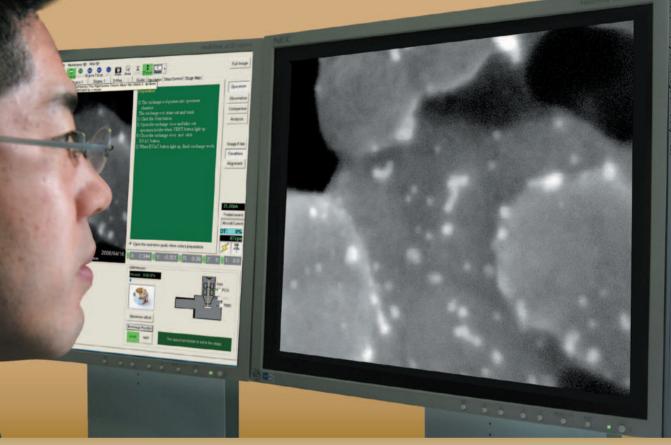






## semi In-Lens FE SEN

## Ultra-high Resolution 6Å @ 30kV True 1,000,000 X Imaging



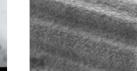


The newest FE SEM from JEOL delivers the ultimate in performance and stability with 1.4nm resolution at 1kV and 0.6nm at 30kV. A patent-pending LABe low angle BSE detector dramatically reduces charging on non-conductive surfaces. Select the contrast that's best for your samples and compare multiple images on-screen from a suite of detectors.

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STEM of nanoparticles Mesoporous Silica

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